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Supporting Information

Chemical Vapor Deposition of MoS₂ Layers from Mo-S-C-O-H System: Thermodynamic Modeling and Validation

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Figure S1(a). SEM image of MoS_2 film grown for 10 minutes on SiO₂. (b) EDS analysis of the film. (c) AFM image of the MoS_2 film.



Figure S2. Mole% of gaseous phases formed in Ar ambient at 20 Torr.



Figure S3. Composition of C and CO₂ formed in Ar:H₂=50:50 at different P.



Figure S4. XRD validating theoretical prediction of Mo_2C-MoS_2 and pure Mo_2C films at 950°C and 1050°C respectively, for high flow rate of H₂ (1000 sccm) at 600 Torr.



Figure S5. Raman spectra for h=1000 sccm to estimate C content in the MoS₂-C films at $T = 850^{\circ}$ C and P = 600 Torr.



Figure S6. Gaseous and solid (S and MoS₃) species with O₂ leak in Ar ambient.



Figure S7. Gaseous and solid species with O_2 leak in the system at different T.

Precursor	Mo(CO) ₆ powder (99.99% purity, Sigma	
	Aldrich)	
Precursor vapor flow rate	7 to 1 sccm	
Reacting gas	H_2S (99.5% from Bhoruka)	
Reacting gas flow rate	1 to10 sccm (Electronic mass flow controllers	
	from MKS Instruments used for regulating gas	
	flow)	
Carrier gas	Ar, H ₂ , and Ar/H ₂ mixture	
Carrier gas flow rate	100 to 1000 sccm	
Total reactor pressure P _{tot}	20 to 700 Torr (maintained using a bellows-	
	sealed throttle valve connected at the mouth of a	
	rotary vane pump, and read by a capacitance	
	manometer)	
Substrate temperature T _{sub}	350°C to 1050°C	
Sublimator temperature	100°C to 130°C	
Substrates used	300 nm thermally grown SiO ₂ on Si, c-plane	
	sapphire, and fused quartz	
Duration of Deposition runs	40 seconds to 10 minutes	

Table S1.	Range	of CVD	conditions	used.
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MoS ₂	Element	Atomic
		percentage
20 Torr, 350C	Mo 3d	1
	S 2s	2.18
	C 1s	4.07
600 Torr, 500C	Mo 3d	1
	S 2s	2.34
	C 1s	1.98
20 Torr, 500C	Mo 3d	1
	S 2s	2.10
	C 1s	0.98
20 Torr, 500C	Mo 3d	1
	S 2s	2.34
	C 1s	0.8

Table S2. Compositional data deduced from XPS spectra.